Application/Control No.	Applicant(s)/Patent under Reexamination	
10/500,609	SHINKAI, KOICHI	
Examiner	Art Unit	
Salvador E. Rivas	2609	

SEARCHED					
Class	Subclass	Date	Examiner		
370	282	3/13/2007	SER		
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INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
		-			

SEARCH NOT (INCLUDING SEARCH		)
	DATE	EXMR
EAST Image and Keyword search in USPAT, US PG-PUB, USOCR, FPRS, EPO, JPO, DERWENT and IBM_TBD (see attached search strategy)	3/13/2007	SER
Inventor name and Assignee search in PALM ExPO and EAST	3/13/2007	SER
EPO Database(http://ep.espacenet.com)	3/13/2007	SER
JPO Database(http://www.ipdl.ncipi.go.jp/ homepg_e.ipdl)	3/14/2007	SER
Consulted with George Bugg and Rafael Perez-Gutierrez	3/15/2007	SER
((first and second) adj receiv\$4) with ((detect\$3 or comparat\$3) and (buffer or memory)) and (signal adj line\$1)	3/14/2007	SER
S19 or "375"/\$.cds.	3/14/2007	SER
PLUS search	3/14/2007	SER